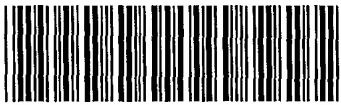


Search Notes

Application No.

10/049,570

Examiner

Anthony Weier

Applicant(s)

TAKAHASHI ET AL.

Art Unit

1761

SEARCHED

Class	Subclass	Date	Examiner
426	594, 618		
	637,	9/29/2003	AW

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR